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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	832
Number of Logic Elements/Cells	8320
Total RAM Bits	106496
Number of I/O	271
Number of Gates	526000
Voltage - Supply	1.71V ~ 1.89V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	356-LBGA
Supplier Device Package	356-BGA (35x35)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/ep20k200ebc356-2x">https://www.e-xfl.com/product-detail/intel/ep20k200ebc356-2x</a>

All APEX 20K devices are reconfigurable and are 100% tested prior to shipment. As a result, test vectors do not have to be generated for fault coverage purposes. Instead, the designer can focus on simulation and design verification. In addition, the designer does not need to manage inventories of different application-specific integrated circuit (ASIC) designs; APEX 20K devices can be configured on the board for the specific functionality required.

APEX 20K devices are configured at system power-up with data stored in an Altera serial configuration device or provided by a system controller. Altera offers in-system programmability (ISP)-capable EPC1, EPC2, and EPC16 configuration devices, which configure APEX 20K devices via a serial data stream. Moreover, APEX 20K devices contain an optimized interface that permits microprocessors to configure APEX 20K devices serially or in parallel, and synchronously or asynchronously. The interface also enables microprocessors to treat APEX 20K devices as memory and configure the device by writing to a virtual memory location, making reconfiguration easy.

After an APEX 20K device has been configured, it can be reconfigured in-circuit by resetting the device and loading new data. Real-time changes can be made during system operation, enabling innovative reconfigurable computing applications.

APEX 20K devices are supported by the Altera Quartus II development system, a single, integrated package that offers HDL and schematic design entry, compilation and logic synthesis, full simulation and worst-case timing analysis, SignalTap logic analysis, and device configuration. The Quartus II software runs on Windows-based PCs, Sun SPARCstations, and HP 9000 Series 700/800 workstations.

The Quartus II software provides NativeLink interfaces to other industry-standard PC- and UNIX workstation-based EDA tools. For example, designers can invoke the Quartus II software from within third-party design tools. Further, the Quartus II software contains built-in optimized synthesis libraries; synthesis tools can use these libraries to optimize designs for APEX 20K devices. For example, the Synopsys Design Compiler library, supplied with the Quartus II development system, includes DesignWare functions optimized for the APEX 20K architecture.

The counter mode uses two three-input LUTs: one generates the counter data, and the other generates the fast carry bit. A 2-to-1 multiplexer provides synchronous loading, and another AND gate provides synchronous clearing. If the cascade function is used by an LE in counter mode, the synchronous clear or load overrides any signal carried on the cascade chain. The synchronous clear overrides the synchronous load. LEs in arithmetic mode can drive out registered and unregistered versions of the LUT output.

### *Clear & Preset Logic Control*

Logic for the register's clear and preset signals is controlled by LAB-wide signals. The LE directly supports an asynchronous clear function. The Quartus II software Compiler can use a NOT-gate push-back technique to emulate an asynchronous preset. Moreover, the Quartus II software Compiler can use a programmable NOT-gate push-back technique to emulate simultaneous preset and clear or asynchronous load. However, this technique uses three additional LEs per register. All emulation is performed automatically when the design is compiled. Registers that emulate simultaneous preset and load will enter an unknown state upon power-up or when the chip-wide reset is asserted.

In addition to the two clear and preset modes, APEX 20K devices provide a chip-wide reset pin (DEV\_CLRn) that resets all registers in the device. Use of this pin is controlled through an option in the Quartus II software that is set before compilation. The chip-wide reset overrides all other control signals. Registers using an asynchronous preset are preset when the chip-wide reset is asserted; this effect results from the inversion technique used to implement the asynchronous preset.

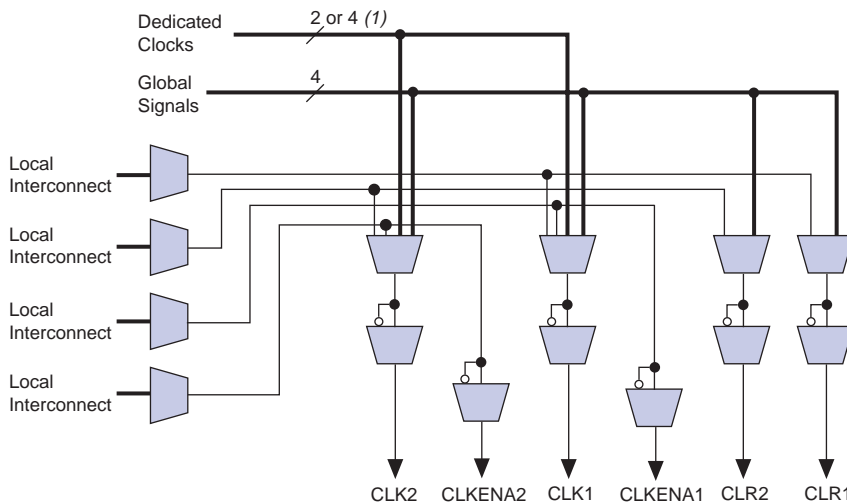
## **FastTrack Interconnect**

In the APEX 20K architecture, connections between LEs, ESBs, and I/O pins are provided by the FastTrack Interconnect. The FastTrack Interconnect is a series of continuous horizontal and vertical routing channels that traverse the device. This global routing structure provides predictable performance, even in complex designs. In contrast, the segmented routing in FPGAs requires switch matrices to connect a variable number of routing paths, increasing the delays between logic resources and reducing performance.

The FastTrack Interconnect consists of row and column interconnect channels that span the entire device. The row interconnect routes signals throughout a row of MegaLAB structures; the column interconnect routes signals throughout a column of MegaLAB structures. When using the row and column interconnect, an LE, IOE, or ESB can drive any other LE, IOE, or ESB in a device. See [Figure 9](#).

The programmable register also supports an asynchronous clear function. Within the ESB, two asynchronous clears are generated from global signals and the local interconnect. Each macrocell can either choose between the two asynchronous clear signals or choose to not be cleared. Either of the two clear signals can be inverted within the ESB. Figure 15 shows the ESB control logic when implementing product-terms.

**Figure 15. ESB Product-Term Mode Control Logic**



**Note to Figure 15:**

(1) APEX 20KE devices have four dedicated clocks.

### Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 32 product terms to feed the macrocell OR logic directly, with two product terms provided by the macrocell and 30 parallel expanders provided by the neighboring macrocells in the ESB.

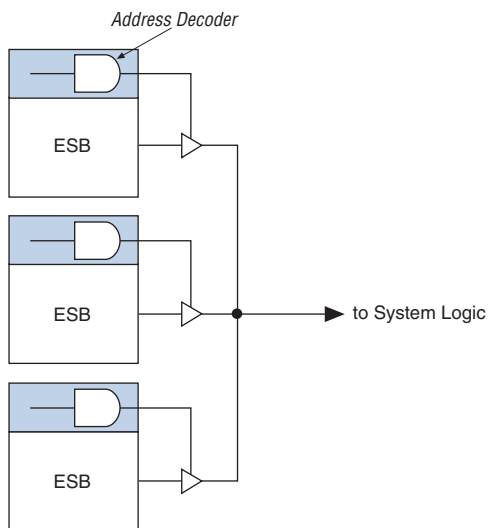
The Quartus II software Compiler can allocate up to 15 sets of up to two parallel expanders per set to the macrocells automatically. Each set of two parallel expanders incurs a small, incremental timing delay. Figure 16 shows the APEX 20K parallel expanders.

ESBs can implement synchronous RAM, which is easier to use than asynchronous RAM. A circuit using asynchronous RAM must generate the RAM write enable (WE) signal, while ensuring that its data and address signals meet setup and hold time specifications relative to the WE signal. In contrast, the ESB's synchronous RAM generates its own WE signal and is self-timed with respect to the global clock. Circuits using the ESB's self-timed RAM must only meet the setup and hold time specifications of the global clock.

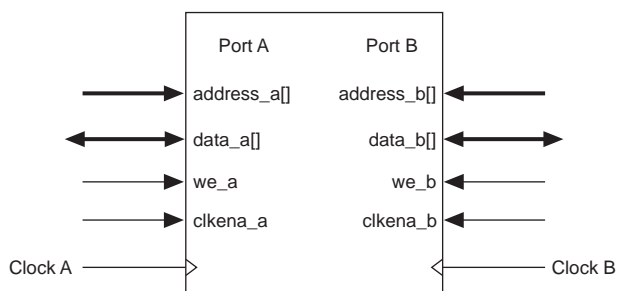
ESB inputs are driven by the adjacent local interconnect, which in turn can be driven by the MegaLAB or FastTrack Interconnect. Because the ESB can be driven by the local interconnect, an adjacent LE can drive it directly for fast memory access. ESB outputs drive the MegaLAB and FastTrack Interconnect. In addition, ten ESB outputs, nine of which are unique output lines, drive the local interconnect for fast connection to adjacent LEs or for fast feedback product-term logic.

When implementing memory, each ESB can be configured in any of the following sizes:  $128 \times 16$ ,  $256 \times 8$ ,  $512 \times 4$ ,  $1,024 \times 2$ , or  $2,048 \times 1$ . By combining multiple ESBs, the Quartus II software implements larger memory blocks automatically. For example, two  $128 \times 16$  RAM blocks can be combined to form a  $128 \times 32$  RAM block, and two  $512 \times 4$  RAM blocks can be combined to form a  $512 \times 8$  RAM block. Memory performance does not degrade for memory blocks up to 2,048 words deep. Each ESB can implement a 2,048-word-deep memory; the ESBs are used in parallel, eliminating the need for any external control logic and its associated delays.

To create a high-speed memory block that is more than 2,048 words deep, ESBs drive tri-state lines. Each tri-state line connects all ESBs in a column of MegaLAB structures, and drives the MegaLAB interconnect and row and column FastTrack Interconnect throughout the column. Each ESB incorporates a programmable decoder to activate the tri-state driver appropriately. For instance, to implement 8,192-word-deep memory, four ESBs are used. Eleven address lines drive the ESB memory, and two more drive the tri-state decoder. Depending on which 2,048-word memory page is selected, the appropriate ESB driver is turned on, driving the output to the tri-state line. The Quartus II software automatically combines ESBs with tri-state lines to form deeper memory blocks. The internal tri-state control logic is designed to avoid internal contention and floating lines. See [Figure 18](#).

**Figure 18. Deep Memory Block Implemented with Multiple ESBs**

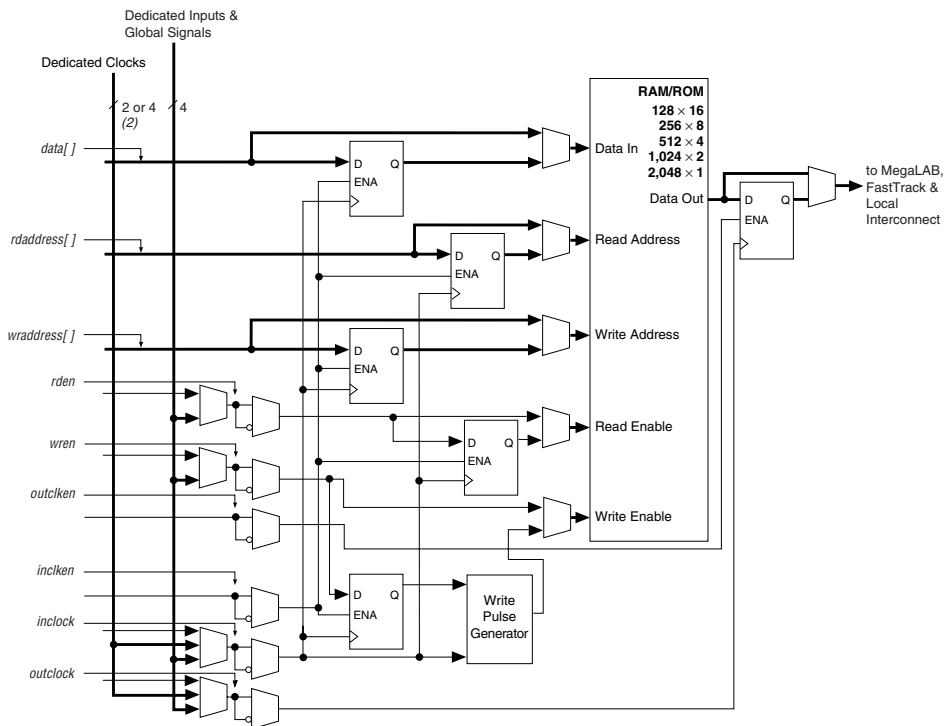
The ESB implements two forms of dual-port memory: read/write clock mode and input/output clock mode. The ESB can also be used for bidirectional, dual-port memory applications in which two ports read or write simultaneously. To implement this type of dual-port memory, two or four ESBs are used to support two simultaneous reads or writes. This functionality is shown in [Figure 19](#).

**Figure 19. APEX 20K ESB Implementing Dual-Port RAM**

## Input/Output Clock Mode

The input/output clock mode contains two clocks. One clock controls all registers for inputs into the ESB: data input, WE, RE, read address, and write address. The other clock controls the ESB data output registers. The ESB also supports clock enable and asynchronous clear signals; these signals also control the reading and writing of registers independently. Input/output clock mode is commonly used for applications where the reads and writes occur at the same system frequency, but require different clock enable signals for the input and output registers. Figure 21 shows the ESB in input/output clock mode.

**Figure 21. ESB in Input/Output Clock Mode** Note (1)



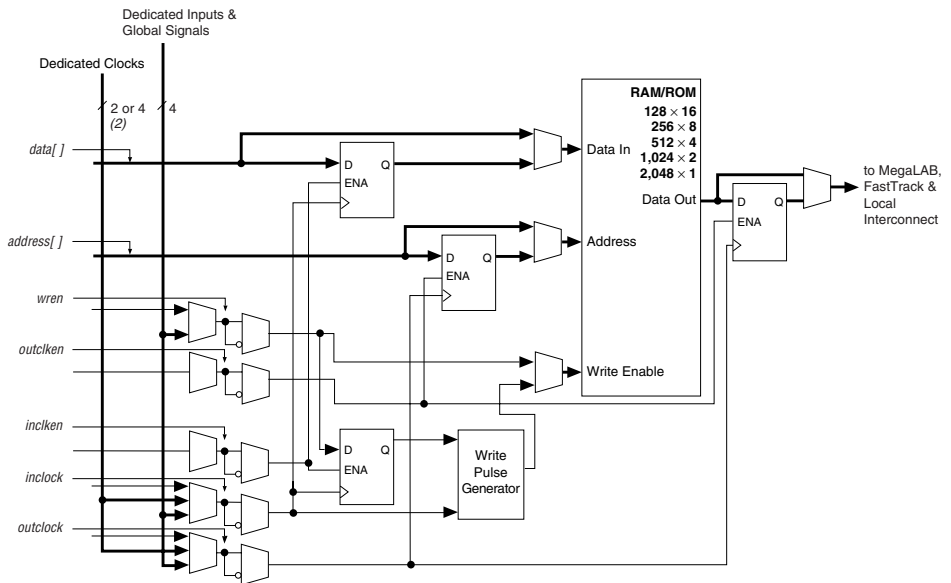
### Notes to Figure 21:

- (1) All registers can be cleared asynchronously by ESB local interconnect signals, global signals, or the chip-wide reset.
- (2) APEX 20KE devices have four dedicated clocks.

## Single-Port Mode

The APEX 20K ESB also supports a single-port mode, which is used when simultaneous reads and writes are not required. See Figure 22.

Figure 22. ESB in Single-Port Mode *Note (1)*



**Notes to Figure 22:**

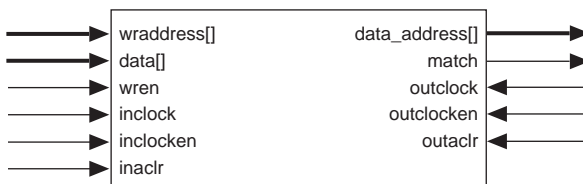
- (1) All registers can be asynchronously cleared by ESB local interconnect signals, global signals, or the chip-wide reset.
- (2) APEX 20KE devices have four dedicated clocks.

**Content-Addressable Memory**

In APEX 20KE devices, the ESB can implement CAM. CAM can be thought of as the inverse of RAM. When read, RAM outputs the data for a given address. Conversely, CAM outputs an address for a given data word. For example, if the data FA12 is stored in address 14, the CAM outputs 14 when FA12 is driven into it.

CAM is used for high-speed search operations. When searching for data within a RAM block, the search is performed serially. Thus, finding a particular data word can take many cycles. CAM searches all addresses in parallel and outputs the address storing a particular word. When a match is found, a match flag is set high. Figure 23 shows the CAM block diagram.



**Figure 23. APEX 20KE CAM Block Diagram**

CAM can be used in any application requiring high-speed searches, such as networking, communications, data compression, and cache management.

The APEX 20KE on-chip CAM provides faster system performance than traditional discrete CAM. Integrating CAM and logic into the APEX 20KE device eliminates off-chip and on-chip delays, improving system performance.

When in CAM mode, the ESB implements 32-word, 32-bit CAM. Wider or deeper CAM can be implemented by combining multiple CAMs with some ancillary logic implemented in LEs. The Quartus II software combines ESBs and LEs automatically to create larger CAMs.

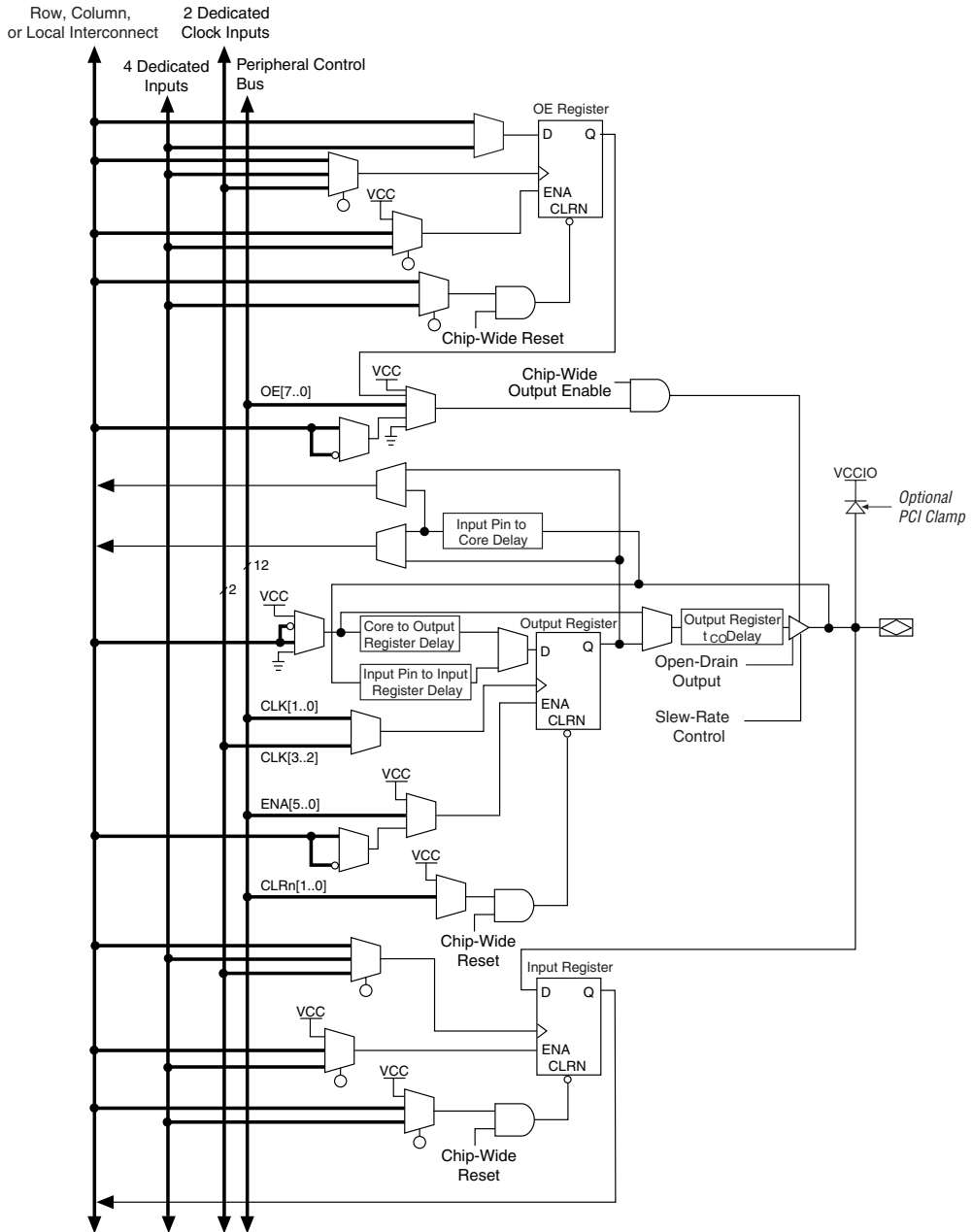
CAM supports writing “don’t care” bits into words of the memory. The “don’t-care” bit can be used as a mask for CAM comparisons; any bit set to “don’t-care” has no effect on matches.

The output of the CAM can be encoded or unencoded. When encoded, the ESB outputs an encoded address of the data’s location. For instance, if the data is located in address 12, the ESB output is 12. When unencoded, the ESB uses its 16 outputs to show the location of the data over two clock cycles. In this case, if the data is located in address 12, the 12th output line goes high. When using unencoded outputs, two clock cycles are required to read the output because a 16-bit output bus is used to show the status of 32 words.

The encoded output is better suited for designs that ensure duplicate data is not written into the CAM. If duplicate data is written into two locations, the CAM’s output will be incorrect. If the CAM may contain duplicate data, the unencoded output is a better solution; CAM with unencoded outputs can distinguish multiple data locations.

CAM can be pre-loaded with data during configuration, or it can be written during system operation. In most cases, two clock cycles are required to write each word into CAM. When “don’t-care” bits are used, a third clock cycle is required.

**Figure 25. APEX 20K Bidirectional I/O Registers** *Note (1)*



**Note to Figure 25:**

(1) The output enable and input registers are LE registers in the LAB adjacent to the bidirectional pin.

### *Clock Phase & Delay Adjustment*

The APEX 20KE ClockShift feature allows the clock phase and delay to be adjusted. The clock phase can be adjusted by 90° steps. The clock delay can be adjusted to increase or decrease the clock delay by an arbitrary amount, up to one clock period.

### *LVDS Support*

Two PLLs are designed to support the LVDS interface. When using LVDS, the I/O clock runs at a slower rate than the data transfer rate. Thus, PLLs are used to multiply the I/O clock internally to capture the LVDS data. For example, an I/O clock may run at 105 MHz to support 840 megabits per second (Mbps) LVDS data transfer. In this example, the PLL multiplies the incoming clock by eight to support the high-speed data transfer. You can use PLLs in EP20K400E and larger devices for high-speed LVDS interfacing.

### *Lock Signals*

The APEX 20KE ClockLock circuitry supports individual LOCK signals. The LOCK signal drives high when the ClockLock circuit has locked onto the input clock. The LOCK signals are optional for each ClockLock circuit; when not used, they are I/O pins.

## **ClockLock & ClockBoost Timing Parameters**

For the ClockLock and ClockBoost circuitry to function properly, the incoming clock must meet certain requirements. If these specifications are not met, the circuitry may not lock onto the incoming clock, which generates an erroneous clock within the device. The clock generated by the ClockLock and ClockBoost circuitry must also meet certain specifications. If the incoming clock meets these requirements during configuration, the APEX 20K ClockLock and ClockBoost circuitry will lock onto the clock during configuration. The circuit will be ready for use immediately after configuration. In APEX 20KE devices, the clock input standard is programmable, so the PLL cannot respond to the clock until the device is configured. The PLL locks onto the input clock as soon as configuration is complete. [Figure 30](#) shows the incoming and generated clock specifications.



For more information on ClockLock and ClockBoost circuitry, see *Application Note 115: Using the ClockLock and ClockBoost PLL Features in APEX Devices*.

**Table 15. APEX 20K ClockLock & ClockBoost Parameters for -1 Speed-Grade Devices (Part 2 of 2)**

Symbol	Parameter	Min	Max	Unit
$t_{\text{SKEW}}$	Skew delay between related ClockLock/ClockBoost-generated clocks		500	ps
$t_{\text{JITTER}}$	Jitter on ClockLock/ClockBoost-generated clock (5)		200	ps
$t_{\text{INCLKSTB}}$	Input clock stability (measured between adjacent clocks)		50	ps

**Notes to Table 15:**

- (1) The PLL input frequency range for the EP20K100-1X device for 1x multiplication is 25 MHz to 175 MHz.
- (2) All input clock specifications must be met. The PLL may not lock onto an incoming clock if the clock specifications are not met, creating an erroneous clock within the device.
- (3) During device configuration, the ClockLock and ClockBoost circuitry is configured first. If the incoming clock is supplied during configuration, the ClockLock and ClockBoost circuitry locks during configuration, because the lock time is less than the configuration time.
- (4) The jitter specification is measured under long-term observation.
- (5) If the input clock stability is 100 ps,  $t_{\text{JITTER}}$  is 250 ps.

Table 16 summarizes the APEX 20K ClockLock and ClockBoost parameters for -2 speed grade devices.

**Table 16. APEX 20K ClockLock & ClockBoost Parameters for -2 Speed Grade Devices**

Symbol	Parameter	Min	Max	Unit
$f_{\text{OUT}}$	Output frequency	25	170	MHz
$f_{\text{CLK1}}$	Input clock frequency (ClockBoost clock multiplication factor equals 1)	25	170	MHz
$f_{\text{CLK2}}$	Input clock frequency (ClockBoost clock multiplication factor equals 2)	16	80	MHz
$f_{\text{CLK4}}$	Input clock frequency (ClockBoost clock multiplication factor equals 4)	10	34	MHz
$t_{\text{OUTDUTY}}$	Duty cycle for ClockLock/ClockBoost-generated clock	40	60	%
$f_{\text{CLKDEV}}$	Input deviation from user specification in the Quartus II software (ClockBoost clock multiplication factor equals one) (1)		25,000 (2)	PPM
$t_{\text{R}}$	Input rise time		5	ns
$t_{\text{F}}$	Input fall time		5	ns
$t_{\text{LOCK}}$	Time required for ClockLock/ ClockBoost to acquire lock (3)		10	μs
$t_{\text{SKEW}}$	Skew delay between related ClockLock/ ClockBoost-generated clock	500	500	ps
$t_{\text{JITTER}}$	Jitter on ClockLock/ ClockBoost-generated clock (4)		200	ps
$t_{\text{INCLKSTB}}$	Input clock stability (measured between adjacent clocks)		50	ps

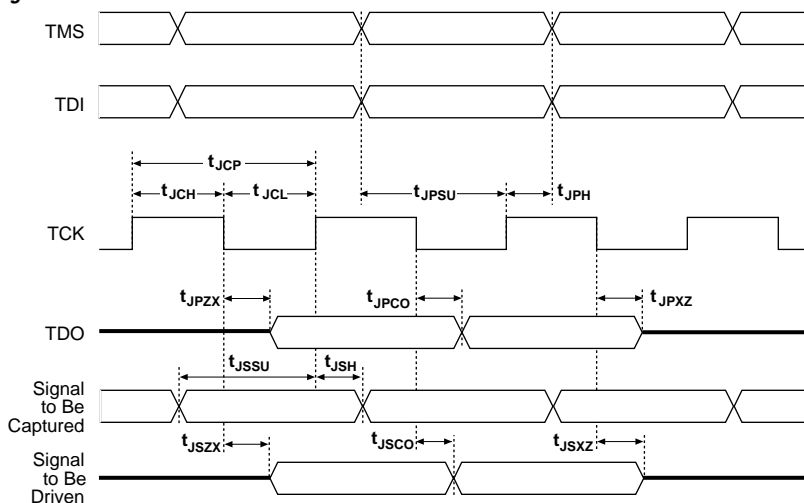
**Table 21. 32-Bit APEX 20K Device IDCODE**

Device	IDCODE (32 Bits) <sup>(1)</sup>			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	1 (1 Bit) <sup>(2)</sup>
EP20K30E	0000	1000 0000 0011 0000	000 0110 1110	1
EP20K60E	0000	1000 0000 0110 0000	000 0110 1110	1
EP20K100	0000	0000 0100 0001 0110	000 0110 1110	1
EP20K100E	0000	1000 0001 0000 0000	000 0110 1110	1
EP20K160E	0000	1000 0001 0110 0000	000 0110 1110	1
EP20K200	0000	0000 1000 0011 0010	000 0110 1110	1
EP20K200E	0000	1000 0010 0000 0000	000 0110 1110	1
EP20K300E	0000	1000 0011 0000 0000	000 0110 1110	1
EP20K400	0000	0001 0110 0110 0100	000 0110 1110	1
EP20K400E	0000	1000 0100 0000 0000	000 0110 1110	1
EP20K600E	0000	1000 0110 0000 0000	000 0110 1110	1
EP20K1000E	0000	1001 0000 0000 0000	000 0110 1110	1

**Notes to Table 21:**

- (1) The most significant bit (MSB) is on the left.  
 (2) The IDCODE's least significant bit (LSB) is always 1.

Figure 31 shows the timing requirements for the JTAG signals.

**Figure 31. APEX 20K JTAG Waveforms**

**Table 24. APEX 20K 5.0-V Tolerant Device Recommended Operating Conditions** *Note (2)*

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CCINT}$	Supply voltage for internal logic and input buffers	(4), (5)	2.375 (2.375)	2.625 (2.625)	V
$V_{CCIO}$	Supply voltage for output buffers, 3.3-V operation	(4), (5)	3.00 (3.00)	3.60 (3.60)	V
	Supply voltage for output buffers, 2.5-V operation	(4), (5)	2.375 (2.375)	2.625 (2.625)	V
$V_I$	Input voltage	(3), (6)	-0.5	5.75	V
$V_O$	Output voltage		0	$V_{CCIO}$	V
$T_J$	Junction temperature	For commercial use	0	85	°C
		For industrial use	-40	100	°C
$t_R$	Input rise time			40	ns
$t_F$	Input fall time			40	ns

**Table 25. APEX 20K 5.0-V Tolerant Device DC Operating Conditions (Part 1 of 2)** *Notes (2), (7), (8)*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IH}$	High-level input voltage		1.7, $0.5 \times V_{CCIO}$ (9)		5.75	V
$V_{IL}$	Low-level input voltage		-0.5		$0.8, 0.3 \times V_{CCIO}$ (9)	V
$V_{OH}$	3.3-V high-level TTL output voltage	$I_{OH} = -8$ mA DC, $V_{CCIO} = 3.00$ V (10)	2.4			V
	3.3-V high-level CMOS output voltage	$I_{OH} = -0.1$ mA DC, $V_{CCIO} = 3.00$ V (10)	$V_{CCIO} - 0.2$			V
	3.3-V high-level PCI output voltage	$I_{OH} = -0.5$ mA DC, $V_{CCIO} = 3.00$ to $3.60$ V (10)	$0.9 \times V_{CCIO}$			V
	2.5-V high-level output voltage	$I_{OH} = -0.1$ mA DC, $V_{CCIO} = 2.30$ V (10)	2.1			V
		$I_{OH} = -1$ mA DC, $V_{CCIO} = 2.30$ V (10)	2.0			V
		$I_{OH} = -2$ mA DC, $V_{CCIO} = 2.30$ V (10)	1.7			V

**Table 28. APEX 20KE Device Recommended Operating Conditions**

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CCINT}$	Supply voltage for internal logic and input buffers	(3), (4)	1.71 (1.71)	1.89 (1.89)	V
$V_{CCIO}$	Supply voltage for output buffers, 3.3-V operation	(3), (4)	3.00 (3.00)	3.60 (3.60)	V
	Supply voltage for output buffers, 2.5-V operation	(3), (4)	2.375 (2.375)	2.625 (2.625)	V
	Supply voltage for output buffers, 1.8-V operation	(3), (4)	1.71 (1.71)	1.89 (1.89)	V
$V_I$	Input voltage	(5), (6)	−0.5	4.0	V
$V_O$	Output voltage		0	$V_{CCIO}$	V
$T_J$	Junction temperature	For commercial use	0	85	° C
		For industrial use	−40	100	° C
$t_R$	Input rise time			40	ns
$t_F$	Input fall time			40	ns

**Table 41. EP20K200  $f_{MAX}$  Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Units
	Min	Max	Min	Max	Min	Max	
$t_{SU}$	0.5		0.6		0.8		ns
$t_H$	0.7		0.8		1.0		ns
$t_{CO}$		0.3		0.4		0.5	ns
$t_{LUT}$		0.8		1.0		1.3	ns
$t_{ESBRC}$		1.7		2.1		2.4	ns
$t_{ESBWC}$		5.7		6.9		8.1	ns
$t_{ESBWESU}$	3.3		3.9		4.6		ns
$t_{ESBDATASU}$	2.2		2.7		3.1		ns
$t_{ESBDATAH}$	0.6		0.8		0.9		ns
$t_{ESBADDRSU}$	2.4		2.9		3.3		ns
$t_{ESBDATACO1}$		1.3		1.6		1.8	ns
$t_{ESBDATACO2}$		2.6		3.1		3.6	ns
$t_{ESBDD}$		2.5		3.3		3.6	ns
$t_{PD}$		2.5		3.0		3.6	ns
$t_{PTERMSU}$	2.3		2.7		3.2		ns
$t_{PTERMCO}$		1.5		1.8		2.1	ns
$t_{F1-4}$		0.5		0.6		0.7	ns
$t_{F5-20}$		1.6		1.7		1.8	ns
$t_{F20+}$		2.2		2.2		2.3	ns
$t_{CH}$	2.0		2.5		3.0		ns
$t_{CL}$	2.0		2.5		3.0		ns
$t_{CLRP}$	0.3		0.4		0.4		ns
$t_{PREP}$	0.4		0.5		0.5		ns
$t_{ESBCH}$	2.0		2.5		3.0		ns
$t_{ESBCL}$	2.0		2.5		3.0		ns
$t_{ESBWP}$	1.6		1.9		2.2		ns
$t_{ESBRP}$	1.0		1.3		1.4		ns



**Table 46. EP20K200 External Bidirectional Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSUBIDIR}} (1)$	1.9		2.3		2.6		ns
$t_{\text{INHBIDIR}} (1)$	0.0		0.0		0.0		ns
$t_{\text{OUTCOBIDIR}} (1)$	2.0	4.6	2.0	5.6	2.0	6.8	ns
$t_{\text{XZBIDIR}} (1)$		5.0		5.9		6.9	ns
$t_{\text{ZXBIDIR}} (1)$		5.0		5.9		6.9	ns
$t_{\text{INSUBIDIR}} (2)$	1.1		1.2		—		ns
$t_{\text{INHBIDIR}} (2)$	0.0		0.0		—		ns
$t_{\text{OUTCOBIDIR}} (2)$	0.5	2.7	0.5	3.1	—	—	ns
$t_{\text{XZBIDIR}} (2)$		4.3		5.0		—	ns
$t_{\text{ZXBIDIR}} (2)$		4.3		5.0		—	ns

**Table 47. EP20K400 External Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}} (1)$	1.4		1.8		2.0		ns
$t_{\text{INH}} (1)$	0.0		0.0		0.0		ns
$t_{\text{OUTCO}} (1)$	2.0	4.9	2.0	6.1	2.0	7.0	ns
$t_{\text{INSU}} (2)$	0.4		1.0		—		ns
$t_{\text{INH}} (2)$	0.0		0.0		—		ns
$t_{\text{OUTCO}} (2)$	0.5	3.1	0.5	4.1	—	—	ns

**Table 48. EP20K400 External Bidirectional Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSUBIDIR}} (1)$	1.4		1.8		2.0		ns
$t_{\text{INHBIDIR}} (1)$	0.0		0.0		0.0		ns
$t_{\text{OUTCOBIDIR}} (1)$	2.0	4.9	2.0	6.1	2.0	7.0	ns
$t_{\text{XZBIDIR}} (1)$		7.3		8.9		10.3	ns
$t_{\text{ZXBIDIR}} (1)$		7.3		8.9		10.3	ns
$t_{\text{INSUBIDIR}} (2)$	0.5		1.0		—		ns
$t_{\text{INHBIDIR}} (2)$	0.0		0.0		—		ns
$t_{\text{OUTCOBIDIR}} (2)$	0.5	3.1	0.5	4.1	—	—	ns
$t_{\text{XZBIDIR}} (2)$		6.2		7.6		—	ns
$t_{\text{ZXBIDIR}} (2)$		6.2		7.6		—	ns

Tables 55 through 60 describe  $f_{MAX}$  LE Timing Microparameters,  $f_{MAX}$  ESB Timing Microparameters,  $f_{MAX}$  Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K60E APEX 20KE devices.

**Table 55. EP20K60E  $f_{MAX}$  LE Timing Microparameters**

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
$t_{SU}$	0.17		0.15		0.16		ns
$t_H$	0.32		0.33		0.39		ns
$t_{CO}$		0.29		0.40		0.60	ns
$t_{LUT}$		0.77		1.07		1.59	ns

**Table 80. EP20K300E  $t_{MAX}$  ESB Timing Microparameters**

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
$t_{ESBARC}$		1.79		2.44		3.25	ns
$t_{ESBSRC}$		2.40		3.12		4.01	ns
$t_{ESBAWC}$		3.41		4.65		6.20	ns
$t_{ESBSWC}$		3.68		4.68		5.93	ns
$t_{ESBWASU}$	1.55		2.12		2.83		ns
$t_{ESBWAH}$	0.00		0.00		0.00		ns
$t_{ESBWDSU}$	1.71		2.33		3.11		ns
$t_{ESBWDH}$	0.00		0.00		0.00		ns
$t_{ESBRASU}$	1.72		2.34		3.13		ns
$t_{ESBRAH}$	0.00		0.00		0.00		ns
$t_{ESBWESU}$	1.63		2.36		3.28		ns
$t_{ESBWEH}$	0.00		0.00		0.00		ns
$t_{ESBDATASU}$	0.07		0.39		0.80		ns
$t_{ESBDATAH}$	0.13		0.13		0.13		ns
$t_{ESBWADDRSU}$	0.27		0.67		1.17		ns
$t_{ESBRADDRSU}$	0.34		0.75		1.28		ns
$t_{ESBDATACO1}$		1.03		1.20		1.40	ns
$t_{ESBDATACO2}$		2.33		3.18		4.24	ns
$t_{ESBDD}$		3.41		4.65		6.20	ns
$t_{PD}$		1.68		2.29		3.06	ns
$t_{PTERMSU}$	0.96		1.48		2.14		ns
$t_{PTERMCO}$		1.05		1.22		1.42	ns

**Table 81. EP20K300E  $t_{MAX}$  Routing Delays**

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
$t_{F1-4}$		0.22		0.24		0.26	ns
$t_{F5-20}$		1.33		1.43		1.58	ns
$t_{F20+}$		3.63		3.93		4.35	ns

**Table 94. EP20K600E Minimum Pulse Width Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t <sub>CH</sub>	2.00		2.50		2.75		ns
t <sub>CL</sub>	2.00		2.50		2.75		ns
t <sub>CLRP</sub>	0.18		0.26		0.34		ns
t <sub>PREP</sub>	0.18		0.26		0.34		ns
t <sub>ESBCH</sub>	2.00		2.50		2.75		ns
t <sub>ESBCL</sub>	2.00		2.50		2.75		ns
t <sub>ESBWP</sub>	1.17		1.68		2.18		ns
t <sub>ESBRP</sub>	0.95		1.35		1.76		ns

**Table 95. EP20K600E External Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t <sub>INSU</sub>	2.74		2.74		2.87		ns
t <sub>INH</sub>	0.00		0.00		0.00		ns
t <sub>OUTCO</sub>	2.00	5.51	2.00	6.06	2.00	6.61	ns
t <sub>INSUPLL</sub>	1.86		1.96		-		ns
t <sub>INHPLL</sub>	0.00		0.00		-		ns
t <sub>OUTCOPLL</sub>	0.50	2.62	0.50	2.91	-	-	ns

**Table 96. EP20K600E External Bidirectional Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t <sub>INSUBIDIR</sub>	0.64		0.98		1.08		ns
t <sub>INHBIDIR</sub>	0.00		0.00		0.00		ns
t <sub>OUTCOBIDIR</sub>	2.00	5.51	2.00	6.06	2.00	6.61	ns
t <sub>XZBIDIR</sub>		6.10		6.74		7.10	ns
t <sub>ZXBIDIR</sub>		6.10		6.74		7.10	ns
t <sub>INSUBIDIRPLL</sub>	2.26		2.68		-		ns
t <sub>INHBIDIRPLL</sub>	0.00		0.00		-		ns
t <sub>OUTCOBIDIRPLL</sub>	0.50	2.62	0.50	2.91	-	-	ns
t <sub>XZBIDIRPLL</sub>		3.21		3.59		-	ns
t <sub>ZXBIDIRPLL</sub>		3.21		3.59		-	ns

**Table 108. EP20K1500E External Bidirectional Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSUBIDIR}}$	3.47		3.68		3.99		ns
$t_{\text{INHBIDIR}}$	0.00		0.00		0.00		ns
$t_{\text{OUTCOBIDIR}}$	2.00	6.18	2.00	6.81	2.00	7.36	ns
$t_{\text{XZBIDIR}}$		6.91		7.62		8.38	ns
$t_{\text{ZXBIDIR}}$		6.91		7.62		8.38	ns
$t_{\text{INSUBIDIRPLL}}$	3.05		3.26				ns
$t_{\text{INHBIDIRPLL}}$	0.00		0.00				ns
$t_{\text{OUTCOBIDIRPLL}}$	0.50	2.67	0.50	2.99			ns
$t_{\text{XZBIDIRPLL}}$		3.41		3.80			ns
$t_{\text{ZXBIDIRPLL}}$		3.41		3.80			ns

Tables 109 and 110 show selectable I/O standard input and output delays for APEX 20KE devices. If you select an I/O standard input or output delay other than LVCMOS, add or subtract the selected speed grade to or from the LVCMOS value.

**Table 109. Selectable I/O Standard Input Delays**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min
LVCMOS		0.00		0.00		0.00	ns
LVTTL		0.00		0.00		0.00	ns
2.5 V		0.00		0.04		0.05	ns
1.8 V		-0.11		0.03		0.04	ns
PCI		0.01		0.09		0.10	ns
GTL+		-0.24		-0.23		-0.19	ns
SSTL-3 Class I		-0.32		-0.21		-0.47	ns
SSTL-3 Class II		-0.08		0.03		-0.23	ns
SSTL-2 Class I		-0.17		-0.06		-0.32	ns
SSTL-2 Class II		-0.16		-0.05		-0.31	ns
LVDS		-0.12		-0.12		-0.12	ns
CTT		0.00		0.00		0.00	ns
AGP		0.00		0.00		0.00	ns